

# AUIRF5210S-VB Datasheet P-Channel 100 V (D-S) MOSFET

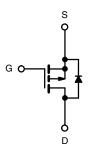
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)		
- 100	0.040 at $V_{GS} = -10 \text{ V}$	- 37	54 nC		
- 100	$0.050$ at $V_{GS} = -4.5 \text{ V}$	- 32	34 110		

#### **FEATURES**

• Trench Power MOSFET







P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (TA :	= 25 °C, unless othe	rwise noted)			
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		$V_{DS}$	- 100	V	
Gate-Source Voltage		$V_{GS}$	± 20	V	
	T <sub>C</sub> = 25 °C		- 37		
Out in the Davis Output (T. 150 00)h	T <sub>C</sub> = 70 °C	1 , [	- 29.5		
Continuous Drain Current (T <sub>J</sub> = 150 °C) <sup>b</sup>	T <sub>A</sub> = 25 °C	- I <sub>D</sub>	- 10 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C	1	- 8.2 <sup>b, c</sup>		
Pulsed Drain Current	I <sub>DM</sub>	- 150	Α		
Continuous Courses Coursest (Diede Conduction)	T <sub>C</sub> = 25 °C		- 50 <sup>a</sup>		
Continuous Source Current (Diode Conduction)	T <sub>A</sub> = 25 °C	l <sub>S</sub>	- 6.75 <sup>b, c</sup>		
Avalanche Current L = 0.1 mH		I <sub>AS</sub>	- 35		
Single Pulse Avalanche Energy		E <sub>AS</sub>	61	mJ	
	T <sub>C</sub> = 25 °C		113.6		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C		72.7	w	
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	6.9 <sup>b, c</sup>	T VV	
	T <sub>A</sub> = 70 °C	1	4.4 <sup>b, c</sup>	1	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Limit	Unit		
Junction-to-Ambient	PCB Mount (TO-263) <sup>c</sup>	R <sub>thJA</sub>	40	°C/W		
Junction-to-Case (Drain)		R <sub>thJC</sub>	2.1	C/VV		

#### Notes:

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

服务热线:400-655-8788

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	•					•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	- 100			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 109		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = - 250 μA		5.9		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 3	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oaka Walkana Busin Oannant	1	V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V			- 1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10	μΑ
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$	- 40			Α
		V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 9.2 A		0.040		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 7.7 A		0.050		Ω
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 9.2 A		38		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			3800		
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 50 V, V <sub>GS</sub> = 0 V, f = 1 MHz		185		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			135		
	Qg	V <sub>DS</sub> = -50 V, V <sub>GS</sub> = -10 V, I <sub>D</sub> = -9.2 A		106	160	nC
Total Gate Charge				54	81	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = -50 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -9.2 \text{ A}$		14		
Gate-Drain Charge	Q <sub>gd</sub>			26		
Gate Resistance	$R_{g}$	f = 1 MHz		4		Ω
Turn-On Delay Time	t <sub>d(on)</sub>			15	25	
Rise Time	t <sub>r</sub>	$V_{DD} = -50 \text{ V}, R_{L} = 6.5 \Omega$		20	30	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong -7.7 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		110	165	
Fall Time	t <sub>f</sub>			100	150	
Turn-On Delay Time	t <sub>d(on)</sub>			42	65	
Rise Time	t <sub>r</sub>	$V_{DD} = -50 \text{ V}, R_{L} = 6.5 \Omega$		160	240	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 7.7 A, $V_{GEN}$ = - 4.5 V, $R_g$ = 1 $\Omega$		100	150	
Fall Time	t <sub>f</sub>			100	150	
<b>Drain-Source Body Diode Characteristics</b>	s			•		
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 50	٨
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 40	Α
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 7.7 A		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			60	90	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 7.7 A, dl/dt = 100 A/μs, T <sub>.I</sub> = 25 °C		150	225	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$ 1_{\rm F} = -7.7 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s, } 1_{\rm J} = 25 ^{\circ}\text{C}$		46		
Reverse Recovery Rise Time	th	t <sub>b</sub>		14		ns

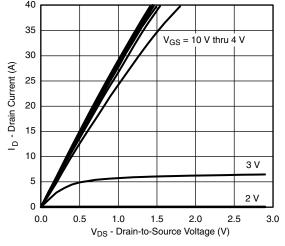
#### Notes:

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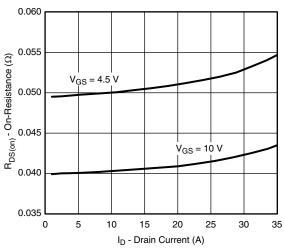
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

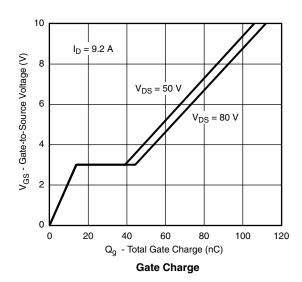


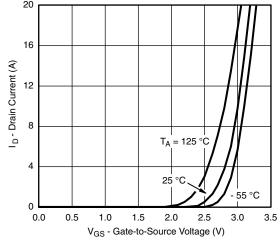


#### **Output Characteristics**

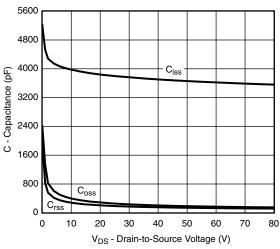


On-Resistance vs. Drain Current and Gate Voltage

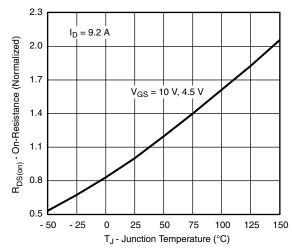




**Transfer Characteristics** 

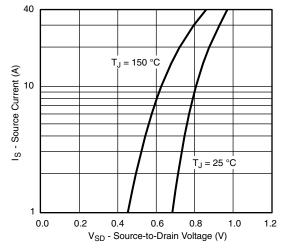


Capacitance

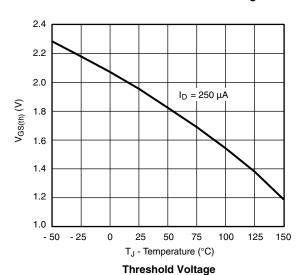


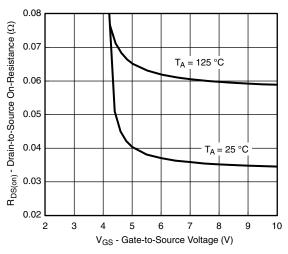
On-Resistance vs. Junction Temperature



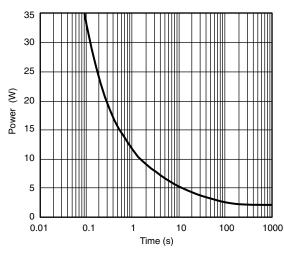




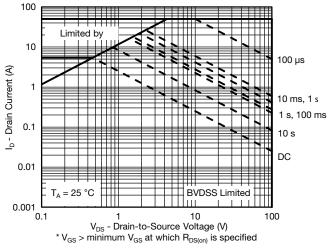




On-Resistance vs. Gate-to-Source Voltage

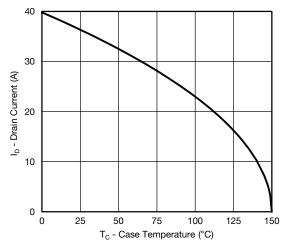


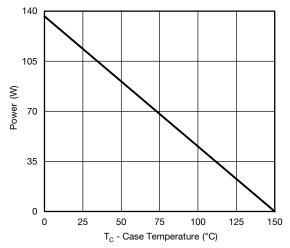
Single Pulse Power, Junction-to-Ambient



Safe Operating Area, Junction-to-Ambient

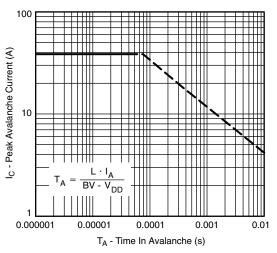






**Current Derating\*** 

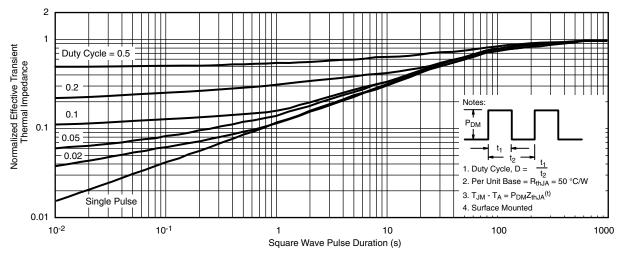
Single Pulse Power, Junction-to-Ambient



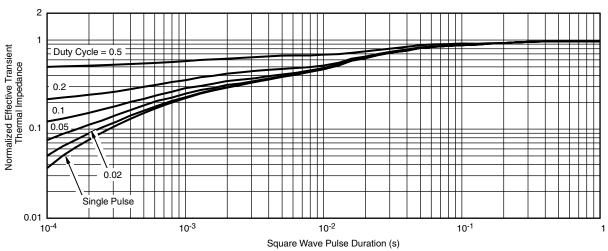
**Single Pulse Avalance Capability** 

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





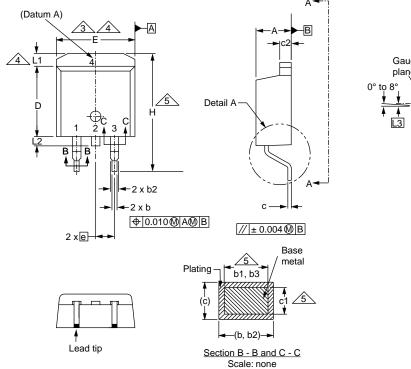
Normalized Thermal Transient Impedance, Junction-to-Ambient

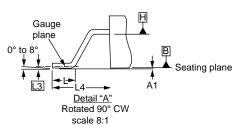


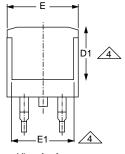
Normalized Thermal Transient Impedance, Junction-to-Case



## **TO-263AB (HIGH VOLTAGE)**







View A - A

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

DIM.     MIN.     MAX.     MIN.     MAX.       D1     6.86     -     0.270     -       E     9.65     10.67     0.380     0.420       E1     6.22     -     0.245     -       e     2.54 BSC     0.100 BSC       H     14.61     15.88     0.575     0.625       L     1.78     2.79     0.070     0.110       L1     -     1.65     -     0.066       L2     -     1.78     -     0.070       L3     0.25 BSC     0.010 BSC       L4     4.78     5.28     0.188     0.208		MILLIMETERS		INC	HES
E   9.65   10.67   0.380   0.420     E1   6.22   -   0.245   -     e   2.54 BSC   0.100 BSC     H   14.61   15.88   0.575   0.625     L   1.78   2.79   0.070   0.110     L1   -   1.65   -   0.066     L2   -   1.78   -   0.070     L3   0.25 BSC   0.010 BSC	DIM.	MIN.	MAX.	MIN.	MAX.
E1 6.22 - 0.245 -   e 2.54 BSC 0.100 BSC   H 14.61 15.88 0.575 0.625   L 1.78 2.79 0.070 0.110   L1 - 1.65 - 0.066   L2 - 1.78 - 0.070   L3 0.25 BSC 0.010 BSC	D1	6.86	-	0.270	-
e     2.54 BSC     0.100 BSC       H     14.61     15.88     0.575     0.625       L     1.78     2.79     0.070     0.110       L1     -     1.65     -     0.066       L2     -     1.78     -     0.070       L3     0.25 BSC     0.010 BSC	Е	9.65	10.67	0.380	0.420
H 14.61 15.88 0.575 0.625   L 1.78 2.79 0.070 0.110   L1 - 1.65 - 0.066   L2 - 1.78 - 0.070   L3 0.25 BSC 0.010 BSC	E1	6.22	-	0.245	-
L 1.78 2.79 0.070 0.110   L1 - 1.65 - 0.066   L2 - 1.78 - 0.070   L3 0.25 BSC 0.010 BSC	е	2.54 BSC		0.100 BSC	
L1 - 1.65 - 0.066 L2 - 1.78 - 0.070 L3 0.25 BSC 0.010 BSC	Н	14.61	15.88	0.575	0.625
L2     -     1.78     -     0.070       L3     0.25 BSC     0.010 BSC	L	1.78	2.79	0.070	0.110
L3 0.25 BSC 0.010 BSC	L1	-	1.65	1	0.066
	L2	-	1.78	1	0.070
L4 4.78 5.28 0.188 0.208	L3	0.25 BSC		0.010	BSC
	L4	4.78	5.28	0.188	0.208

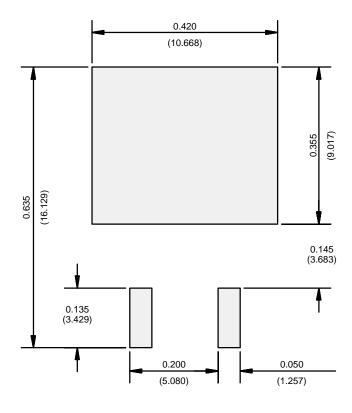
ECN: S-82110-Rev. A, 15-Sep-08

DWG: 5970

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.



## RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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